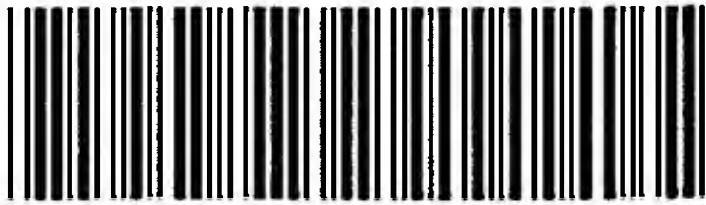


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/711,996	CHEN ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	VAN T. PHAM	2627	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (US-PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB)  369 and 369/53.31, 47. (text search only see search history printout).	2/14/2007	VP